L Number	Hits	Search Text	DB	Time stamp
1	1004	(CRC or(cyclic adj2 redundancy adj2 check)) adj3 generator	USPAT; EPO; JPO; DERWENT	2004/06/16 12:23
2	352	((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1	USPAT; EPO; JPO; DERWENT	2004/06/16 12:24
3	122	((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1)	USPAT; EPO; JPO; DERWENT	2004/06/16 12:25
4	42	((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or	USPAT; EPO; JPO; DERWENT	2004/06/16 12:25
5	10	selector\$1) same ("XOR" or logic) (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) same	USPAT; EPO; JPO; DERWENT	2004/06/16 12:27
6	23	polynomial\$1 (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) and	USPAT; EPO; JPO; DERWENT	2004/06/16 12:27
7	19	polynomial\$1 (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) and	USPAT; EPO; JPO; DERWENT	2004/06/16 12:39
11	0	polynomial\$1 and processor\$1 (714/781.ccls.) and (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) and polynomial\$1 and processor\$1 and (configur\$5 or	USPAT; EPO; JPO; DERWENT	2004/06/16 12:30
9	11	program\$5) and dynamic\$4 (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) and polynomial\$1 and processor\$1 and	USPAT; EPO; JPO; DERWENT	2004/06/16 12:30
10	6	(configur\$5 or program\$5) and dynamic\$4 (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same (shift adj3 register\$1) same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) and polynomial\$1 and processor\$1 and	USPAT; EPO; JPO; DERWENT	2004/06/16 12:30
8	19	(configur\$5 or program\$5) and dynamic\$4 (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same register\$1 same (multiplexer\$1 or MUX\$1 or selector\$1) same ("XOR" or logic)) and polynomial\$1 and processor\$1 and	USPAT; EPO; JPO; DERWENT	2004/06/16 12:31
13	8	(configur\$5 or program\$5) (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) and (shift adj2 register\$1) and (multiplexer\$1 or MUX\$1 or selector\$1) and ("XOR" or logic)) and polynomial\$1 and processor\$1 and (dynamic\$4 near3 (configur\$4 or	USPAT; EPO; JPO; DERWENT	2004/06/16 12:40
12	96	program\$5)) (((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) and (shift adj2 register\$1) and (multiplexer\$1 or MUX\$1 or selector\$1) and ("XOR" or logic)) and	USPAT; EPO; JPO; DERWENT	2004/06/16 13:20
14	1	polynomial\$1 and processor\$1 ((CRC or (cyclic adj2 redundancy adj2 check)) adj3 generator) same (pre-select\$4 near3 polynomial\$1)	USPAT; EPO; JPO; DERWENT	2004/06/16 13:23

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15	2	((CRC or (cyclic adj2 redundancy adj2	USPAT;	2004/06/16
	į	check)) adj3 generator) and (pre-select\$4	EPO; JPO;	13:27
		near3 polynomial\$1)	DERWENT	
16	10	((CRC or (cyclic adj2 redundancy adj2	USPAT;	2004/06/16
		check)) adj3 generator) same (N-bit)	EPO; JPO;	13:27
			DERWENT	
17	59	((CRC or (cyclic adj2 redundancy adj2	USPAT;	2004/06/16
		check)) adj3 generator) and (N-bit)	EPO; JPO;	13:34
			DERWENT	

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O- By Author O- Basic O- Advanced	1 Parallel CRC generation Albertengo, G.; Sisto, R.; Micro, IEEE, Volume: 10, Issue: 5, Oct. 1990
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